TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L^2 - π -MOSV)

2SK2200

Chopper Regulator, DC-DC Converter and Motor Drive Applications

• 4-V gate drive

 $\begin{array}{ll} \bullet & Low\ drain-source\ ON\ resistance & : R_{DS}\ (ON) = 0.28\ \Omega\ (typ.) \\ \bullet & High\ forward\ transfer\ admittance & : |Y_{fs}| = 3.5\ S\ (typ.) \\ \bullet & Low\ leakage\ current & : I_{DSS} = 100\ \mu A\ (max)\ (V_{DS} = 100\ V) \\ \bullet & Enhancement\ mode & : V_{th} = 0.8 \\ \sim 2.0\ V\ (V_{DS} = 10\ V,\ I_{D} = 1\ mA) \end{array}$

Absolute Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	100	V
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	100	V
Gate-source voltage		V _{GSS}	±20	V
Drain current	DC (Note 1)	ID	3	Α
Drain current	Pulse (Note 1)	I _{DP}	12	Α
Drain power dissipation (Tc = 25°C)		P_{D}	1.3	W
Single pulse avalanche energy (Note 2)		E _{AS}	140	mJ
Avalanche current		I _{AR}	3	Α
Repetitive avalanche energy (Note 3)		E _{AR}	0.13	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C

Weight: 0.54 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient	R _{th (ch-a)}	96.1	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 50 V, T_{ch} = 25°C (initial), L = 25 mH, R_G = 25 Ω , I_{AR} = 3 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.



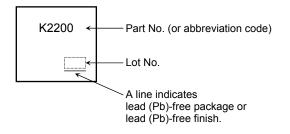
Electrical Characteristics (Ta = 25°C)

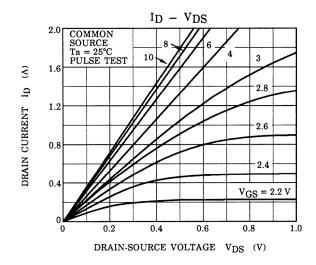
Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V	_	_	100	μA
Drain-source br voltage	reakdown	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	100	_	-	V
Gate threshold	/oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V
Duelle course ON societae		D== (=+)	V _{GS} = 4 V, I _D = 2 A	_	0.36	0.45	mΩ
Drain-source ON resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 2 A	_	0.28	0.35		
Forward transfe	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 2 A	1.5	3.5	_	S
Input capacitano	ce	C _{iss}		_	280	_	
Reverse transfe	r capacitance	C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	50	_	pF
Output capacitance		C _{oss}		_	105	_	
Switching time	Rise time	t _r	$V_{GS} \stackrel{10 \text{ V}}{\text{OUT}} \prod_{\text{I}} \stackrel{I_{\text{D}}}{\text{I}} = 2 \text{ A} \text{ OUT}$	-	20	_	
	Turn-on time	t _{on}	$R_{L} = 25 \Omega$ $V_{DD} = 50 V$	_	50	_	20
	Fall time	t _f		_	40	_	ns
	Turn-off time	t _{off}	Duty \leq 1%, $t_{\mathbf{W}} = 10 \mu\text{s}$	_	170	_	
Total gate charge (Gate-source plus gate-drain)		Qg			13.5		
Gate-source charge		Q _{gs}	$V_{DD} \approx 80 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}$		8.5		nC
Gate-drain ("miller") charge		Q _{gd}		_	5	_	

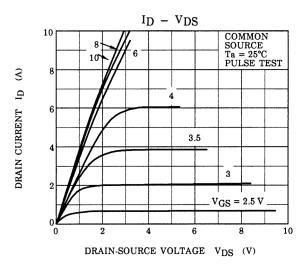
Source-Drain Ratings and Characteristics (Ta = 25°C)

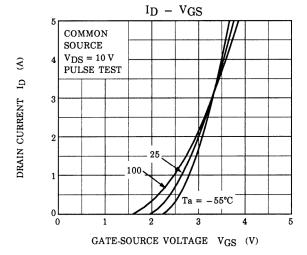
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	3	А
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	12	Α
Forward voltage (diode)	V_{DSF}	I _{DR} = 3 A, V _{GS} = 0 V	_	_	-1.5	V
Reverse recovery time	t _{rr}	$I_{DR} = 3 \text{ A}, V_{GS} = 0 \text{ V}, dI_{DR} / dt = 50 \text{ A} / \mu \text{s}$		100	_	ns
Reverse recovered charge	Qrr		_	0.2	_	μC

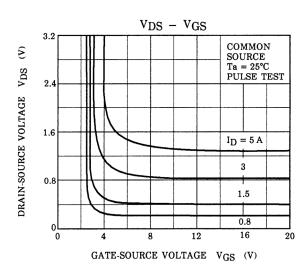
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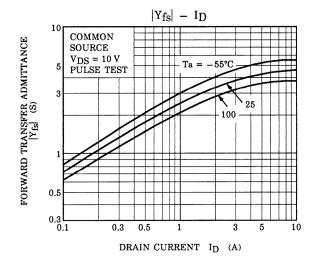


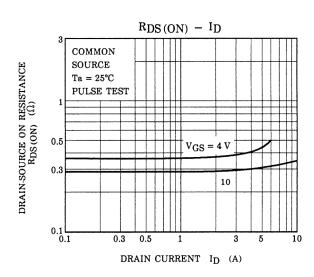


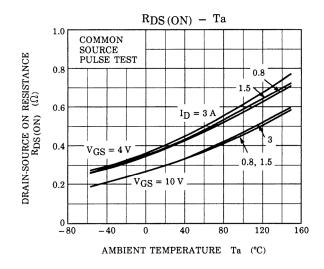


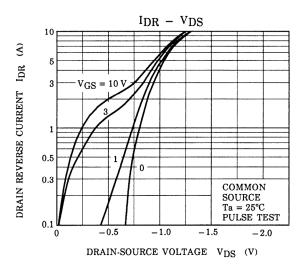


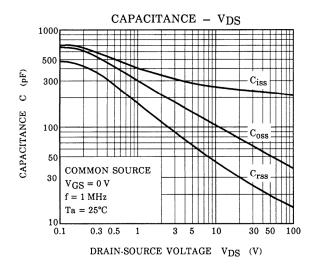


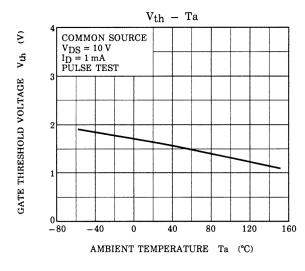


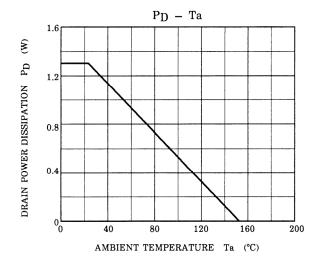


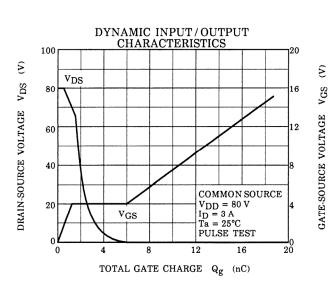


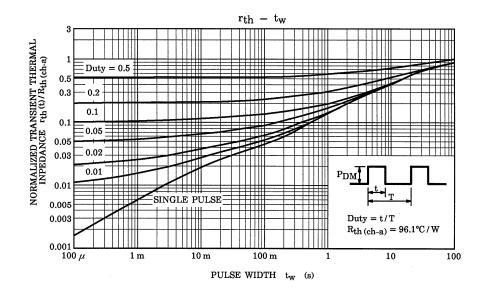


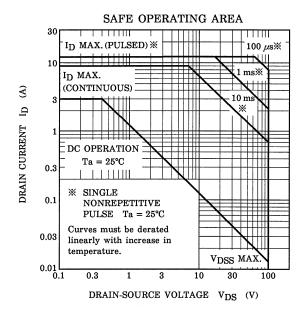


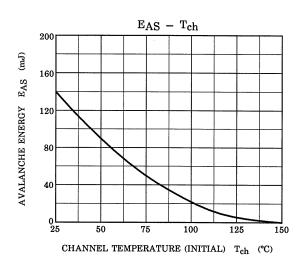


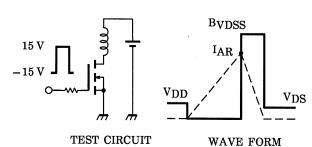












$$\begin{aligned} &R_G = 25 \ \Omega \\ &V_{DD} = 25 \ V, \ L = 25 \ mH \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

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